Supporting Information

Ferroelectrically modulated ultrasensitive two-dimensional

perovskite phototransistor with zero-gate-bias

Junyi She,^a Hanlin Cen,^b Zhiheng Shen,^a Jianyu Wang,^a Xin Liu,^a Jun Xi,^b Yonghong Cheng,^a Guodong Meng^{*a}

^aState Key Laboratory of Electrical Insulation and Power Equipment, Xi'an Jiaotong University, Xi'an, 710049, China.

^bSchool of Electronic Science and Engineering, Xi'an Jiaotong University, Xi'an, 710049, China.

Guodong Meng* - Email: gdmengxjtu@xjtu.edu.cn



Fig. S1 Optical microscopy image of the fabricated phototransistor under illumination with a photosensitive area of 28.5 μ m².



Fig. S2 Contact potential difference maps of $(PEA)_2SnI_4$ on Al:HfO₂ ferroelectric film in Fresh (without polarization), P_{up} (upward polarization) and P_{down} (downward polarization) states through KPFM measurements.



Fig. S3. Optoelectronic performances of SiO₂/(PEA)₂SnI₄ phototransistor. (a) Transfer curve of the proposed device. (b) Output curves under different illumination powers of the fabricated device. (c) Incident light power dependence of responsivity (R) and detectivity (D^*) at V_g =20 V.



Fig. S4 Output curves of the ferroelectric-gated device under varied illumination powers, and the incident light power dependence of responsivity (R) and detectivity (D^*) in (a) Fresh (without polarization) and (b) P_{dwon} (downward polarization) state, respectively.